


<b>Search Notes</b>  	<b>Application/Control No.</b>  10552947	<b>Applicant(s)/Patent Under Reexamination</b>  BARKER, RICHARD J.
	<b>Examiner</b>  Nguyen, Hiep	<b>Art Unit</b>  2816

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (see attachment)	11-18-08	Hn

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
327	423,427,430,434-437,108,538,50,541	11-18-08	Hn
361	91.1	11-18-08	Hn

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